

Search Notes

Application/Control No.

10/098,508

Examiner

Quynh H. Nguyen

Applicant(s)/Patent under
Reexamination

WEIK ET AL.

Art Unit

2614

SEARCHED

Class	Subclass	Date	Examiner
379	111 203.01 214.01 218.02 265.01	2/20/07	QN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched: East, USPGPub,USPAT	2/20/07	QN
Inventor searched through PALM database	2/20/07	QN